

HAC RF TESTREPORT

No. I17Z60754-SEM04

For

HMD Global Oy

Smart Phone

Model Name: TA-1025

With

Hardware Version: 5

Software Version: 000C 3 24A

FCC ID: 2AJOTTA-1025

Results Summary: M Category = M4

Issued Date: 2017-5-31



Note:

The test results in this test report relate only to the devices specified in this report. This report shall not be reproduced except in full without the written approval of CTTL.

Test Laboratory:

CTTL, Telecommunication Technology Labs, Academy of Telecommunication Research, MIIT No. 51 Shouxiang Science Building, Xueyuan Road, Haidian District, Beijing, P. R. China100191 Tel:+86(0)10-62304633-2512,Fax:+86(0)10-62304633-2504

Email: cttl terminals@catr.cn, website: www.chinattl.com



REPORT HISTORY

Report Number	Revision	Issue Date	Description
I17Z60754-SEM04	Rev.0	2017-5-31	Initial creation of test report



TABLE OF CONTENT

1 TEST LABORATORY	5
1.1 TESTING LOCATION	5
1.2 TESTING ENVIRONMENT.	
1.3 Project Data	5
1.4 Signature	5
2 CLIENT INFORMATION	6
2.1 APPLICANT INFORMATION	6
2.2 Manufacturer Information	6
3 EQUIPMENT UNDER TEST (EUT) AND ANCILLARY EQUIPMENT (AE)	7
3.1 About EUT	7
3.2 INTERNAL IDENTIFICATION OF EUT USED DURING THE TEST	7
3.3 INTERNAL IDENTIFICATION OF AE USED DURING THE TEST	
3.4 AIR INTERFACES / BANDS INDICATING OPERATING MODES	7
4 CONDUCTED OUTPUT POWER MEASUREMENT	8
4.1 Summary	
4.2 CONDUCTED POWER	8
5 REFERENCE DOCUMENTS	9
5.1 Reference Documents for testing	9
6 OPERATIONAL CONDITIONS DURING TEST	10
6.1 HAC MEASUREMENT SET-UP	10
6.2 PROBE SPECIFICATION	
6.3TEST ARCH PHANTOM &PHONE POSITIONER	
6.4ROBOTIC SYSTEM SPECIFICATIONS	12
7 EUT ARRANGEMENT	13
7.1 WD RF Emission Measurements Reference and Plane	13
8 SYSTEM VALIDATION	14
8.1 VALIDATION PROCEDURE	14
8.2 VALIDATION RESULT	
9 EVALUATION OF MIF	15
9.1 Introduction	15
9.2 MIF MEASUREMENT WITH THE AIA	
9.3 TEST EQUIPMENT FOR THE MIF MEASUREMENT	
9.4 TEST SIGNAL VALIDATION	
9.5 DUTMIF RESULTS	
10 EVALUATION FOR LOW-POWER EXEMPTION	19
10.1 Product testing threshold	
10.2 CONDUCTED POWER	



10.3 CONCLUSION	19
11 RF TEST PROCEDUERES	20
12 MEASUREMENT RESULTS (E-FIELD)	21
13 ANSIC 63.19-2011 LIMITS	21
14 MEASUREMENT UNCERTAINTY	22
15 MAIN TEST INSTRUMENTS	23
16 CONCLUSION	23
ANNEX A TEST LAYOUT	24
ANNEX B TEST PLOTS	25
ANNEX C SYSTEM VALIDATION RESULT	31
ANNEX D PROBE CALIBRATION CERTIFICATE	33
ANNEX E DIPOLE CALIBRATION CERTIFICATE	43



1 Test Laboratory

1.1 Testing Location

Company Name:	CTTL(Shouxiang)
Address:	No. 51 Shouxiang Science Building, Xueyuan Road, Haidian District,
	Beijing, P. R. China100191

1.2 Testing Environment

Temperature:	18°C~25°C,
Relative humidity:	30%~ 70%
Ground system resistance:	< 0.5 Ω

Ambient noise is checked and found very low and in compliance with requirement of standards. Reflection of surrounding objects is minimized and in compliance with requirement of standards

1.3 Project Data

Project Leader:	Qi Dianyuan
Test Engineer:	Lin Hao
Testing Start Date:	May 22, 2017
Testing End Date:	May 22, 2017

1.4 Signature

Lin Xiaojun

(Prepared this test report)

Qi Dianyuan

(Reviewed this test report)

Lu Bingsong

Deputy Director of the laboratory

(Approved this test report)



2 Client Information

2.1 Applicant Information

Company Name:	HMD Global Oy
Address /Post:	Karaportti 2, 02610 Espoo, Finland
Contact Person:	Mikko Kahlos
E-mail:	mikko.kahlos@hmdglobal.com
Telephone:	+358-408036126

2.2 Manufacturer Information

Company Name:	HMD Global Oy
Address /Post:	Karaportti 2, 02610 Espoo, Finland
Contact Person:	Mikko Kahlos
E-mail:	mikko.kahlos@hmdglobal.com
Telephone:	+358-408036126



3 Equipment Under Test (EUT) and Ancillary Equipment (AE)

3.1 About EUT

Description:	Smart Phone
Model name:	TA-1025
Operating mode(s):	GSM 850/900/1800/1900, WCDMA850/900/1700/1900/2100
	LTE B2/3/4/7/12/17/28/38, BT, WLAN

3.2 Internal Identification of EUT used during the test

EUT ID*	IMEI	HW Version	SW Version
EUT1	356021080010214	5	000C_3_24A
EUT2	356021080009762	5	000C_3_24A

^{*}EUT ID: is used to identify the test sample in the lab internally.

Note: It is performed to test HAC with the EUT1 and conducted power with the EUT2.

3.3 Internal Identification of AE used during the test

AE ID*	Description	Model	SN	Manufacturer
AE1	Battery	HE316	/	SCUD
AE2	Battery	HE317	/	SCUD
AE3	Headset	CAB5422B-N01-DG	/	Foxconn

^{*}AE ID: is used to identify the test sample in the lab internally.

Note: It is performed to test HAC with the AE2.

3.4 Air Interfaces / Bands Indicating Operating Modes

Air-interface	Band(MHz)	Туре	C63.19/tested	Simultaneous Transmissions	ОТТ	Power Reduction
GSM	850	vo	Yes	DT W/ AN	NA	NIA
GSIVI	1900	7 00				NA
GPRS/EDGE	850	DT	NA	BT, WLAN		Nie
GPRS/EDGE	1900	יטך	INA			No
	850				NA	
WCDMA	1700	VO	Yes	BT, WLAN		NA
(UMTS)	1900					
	HSPA	DT	NA			
LTE	Band 2/4/7/12/17/38	V/D.	NA	BT, WLAN	NA	NA
BT	2450	DT	NA	GSM, WCDMA, LTE	NA	NA
WLAN	2450	DT	NA	GSM, WCDMA, LTE	NA	NA

VO: Voice CMRS/PSTN Service Only V/D: Voice CMRS/PSTN and Data Service DT: Digital Transport

Note:1.= No Associated T-Coil measurement has been made in accordance with 285076 D02 T-Coil testing for CMRS IP

^{*} HAC Rating was not based on concurrent voice and data modes, Non current mode was found to represent worst case rating for both M and T rating



4 CONDUCTED OUTPUT POWER MEASUREMENT

4.1 Summary

During the process of testing, the EUT was controlled via Agilent Digital Radio Communication tester (E5515C) to ensure the maximum power transmission and proper modulation. This result contains conducted output power for the EUT. In all cases, the measured output power should be greater and within 5% than EMI measurement.

4.2 Conducted Power

CCM		Conducted Power (dBm)		
GSM 850MHz	Channel 251(848.8MHz)	Channel 190(836.6MHz)	Channel 128(824.2MHz)	
OSUMINZ	33.39	33.36	33.27	
GSM 1900MHz		Conducted Power(dBm)		
	Channel 810(1909.8MHz)	Channel 661(1880MHz)	Channel 512(1850.2MHz)	
1900IVITZ	30.48	30.21	30.26	
MCDMA		Conducted Power (dBm)		
WCDMA 850MHz	Channel 4233(846.6MHz)	Channel 4182(836.4MHz)	Channel 4132(826.4MHz)	
OOUWINZ	24.32	24.35	24.34	
MCDMA		Conducted Power (dBm)		
WCDMA	Channel 1513 (1752.6MHz)	Channel 1412 (1732.4MHz)	Channel 1312 (1712.4MHz)	
1700MHz	23.89	23.93	23.86	
MCDMA		Conducted Power (dBm)		
WCDMA 1900MHz	Channel 9538(1907.6MHz)	Channel 9400(1880MHz)	Channel 9262(1852.4MHz)	
1900101112	24.15	24.09	23.96	
LTE		Conducted Power (dBm)		
Band2	Channel 19100(1900MHz)	Channel18900(1880MHz)	Channel 18700(1860MHz)	
QPSK	24.78	24.58	24.80	
LTE		Conducted Power (dBm)		
Band4	Channel 20300(1745MHz)	Channel20175(1732.5MHz)	Channel 20050(1720MHz)	
QPSK	24.55	24.62	24.80	
LTE		Conducted Power (dBm)		
Band7	Channel 21350(2560MHz)	Channel21100(2535MHz)	Channel 20850(2510MHz)	
QPSK	24.41	24.23	24.16	
LTE		Conducted Power (dBm)		
Band12	Channel 23130(711MHz)	Channel 23095(707.5MHz)	Channel23060(704MHz)	
QPSK	24.32	24.31	24.02	
LTE	Conducted Power (dBm)			
Band17	Channel23800(711MHz)	Channel23790(710MHz)	Channel23780(709MHz)	
QPSK	22.98	23.11	23.17	
LTE	Conducted Power (dBm)			
Band38	Channel38150(2610MHz)	Channel38000(2595MHz)	Channel37850(2580MHz)	
QPSK	24.44	24.47	24.31	



LTE		Conducted Power (dBm)		
Band2	Channel 19100(1900MHz)	Channel18900(1880MHz)	Channel 18700(1860MHz)	
16-QAM	23.28	23.61	23.20	
LTE		Conducted Power (dBm)		
Band4	Channel 20300(1745MHz)	Channel20175(1732.5MHz)	Channel 20050(1720MHz)	
16-QAM	23.46	23.67	23.36	
LTE	Conducted Power (dBm)			
Band7	Channel 21350(2560MHz)	Channel21100(2535MHz)	Channel 20850(2510MHz)	
16-QAM	22.80	22.89	22.61	
LTE		Conducted Power (dBm)		
Band12	Channel 23130(711MHz)	Channel 23095(707.5MHz)	Channel23060(704MHz)	
16-QAM	23.41	23.65	23.22	
LTE		Conducted Power (dBm)		
Band17	Channel23800(711MHz)	Channel23790(710MHz)	Channel23780(709MHz)	
16-QAM	22.56	22.89	22.59	
LTE	Conducted Power (dBm)			
Band38	Channel38150(2610MHz)	Channel38000(2595MHz)	Channel37850(2580MHz)	
16-QAM	22.90	22.80	22.74	

5 Reference Documents

5.1 Reference Documents for testing

The following document listed in this section is referred for testing.

Reference	Title	Version		
ANSI C63.19-2011	American National Standard for Methods of Measurement of	2011		
	Compatibility between Wireless Communication Devices and	Edition		
	Hearing Aids			
FCC 47 CFR §20.19	Hearing Aid Compatible Mobile Headsets			
KDB 285076 D01	Equipment Authorization Guidance for Hearing Aid Compatibility	v04		



6 OPERATIONAL CONDITIONS DURING TEST

6.1 HAC MEASUREMENT SET-UP

These measurements are performed using the DASY5 NEO automated dosimetric assessment system. It is made by Schmid & Partner Engineering AG (SPEAG) in Zurich, Switzerland. It consists of high precision robotics system (Stäubli), robot controller, Intel Core2 computer, near-field probe, probe alignment sensor. The robot is a six-axis industrial robot performing precise movements. A cell controller system contains the power supply, robot controller, teach pendant (Joystick),and remote control, is used to drive the robot motors. The PC consists of the HP Intel Core21.86 GHz computer with Windows XP system and HAC Measurement Software DASY5 NEO, A/D interface card, monitor, mouse, and keyboard. The Stäubli Robot is connected to the cell controller to allow software manipulation of the robot. A data acquisition electronic (DAE)circuit performs the signal amplification, signal multiplexing, AD-conversion, offset measurements, mechanical surface detection, collision detection, etc. is connected to the Electro-optical coupler (EOC). The EOC performs the conversion from the optical into digital electric signal of the DAE and transfers data to the PC plug-in card.

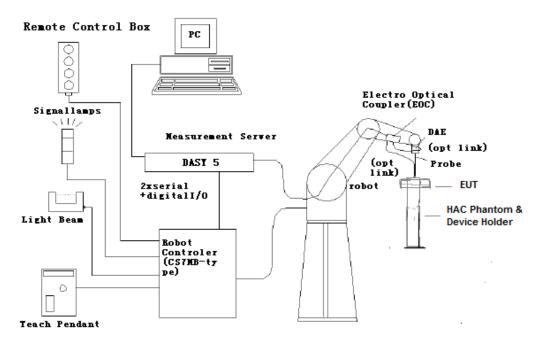


Fig. 1 HAC Test Measurement Set-up

The DAE4 consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the PC-card is accomplished through an optical downlink for data and status information and an optical uplink for commands and clock lines. The mechanical probe mounting device includes two different sensor systems for frontal and sidewise probe contacts. They are also used for mechanical surface detection and probe collision detection. The robot uses its own controller with a built in VME-bus computer.



6.2 Probe Specification

E-Field Probe Description

Construction One dipole parallel, two dipoles normal to probe axis

Built-in shielding against static charges

PEEK enclosure material

Calibration In air from 100 MHz to 3.0 GHz (absolute accuracy ±6.0%,

k=2)

Frequency 40 MHz to > 6 GHz (can be extended to < 20 MHz)

Linearity: ± 0.2 dB (100 MHz to 3 GHz)

Directivity ± 0.2 dB in air (rotation around probe axis)

± 0.4 dB in air (rotation normal to probe axis)

Dynamic Range 2 V/m to > 1000 V/m; Linearity: ± 0.2 dB

Dimensions Overall length: 330 mm (Tip: 16 mm)

Tip diameter: 8 mm (Body: 12 mm)

Distance from probe tip to dipole centers: 2.5 mm

Application General near-field measurements up to 6 GHz

Field component measurements

Fast automatic scanning in phantoms



[ER3DV6]



6.3 Test Arch Phantom & Phone Positioner

The Test Arch phantom should be positioned horizontally on a stable surface. Reference markings on the Phantom allow the complete setup of all predefined phantom positions and measurement grids by manually teaching three points in the robot. It enables easy and well defined positioning of the phone and validation dipoles as well as simple teaching of the robot (Dimensions: $370 \times 370 \times 370 \text{ mm}$).

The Phone Positioner supports accurate and reliable positioning of any phone with effect on near field $<\pm 0.5$ dB.



Fig. 2 HAC Phantom & Device Holder

6.4 Robotic System Specifications

Specifications

Positioner: Stäubli Unimation Corp. Robot Model: RX160L

Repeatability: ±0.02 mm

No. of Axis: 6

Data Acquisition Electronic (DAE) System

Cell Controller

Processor: Intel Core2 Clock Speed: 1.86GHz

Operating System: Windows XP

Data Converter

Features: Signal Amplifier, multiplexer, A/D converter, and control logic

Software: DASY5 software

Connecting Lines: Optical downlink for data and status info.

Optical uplink for commands and clock



7 EUT ARRANGEMENT

7.1 WD RF Emission Measurements Reference and Plane

Figure 4 illustrates the references and reference plane that shall be used in the WD emissions measurement.

- The grid is 5 cm by 5 cm area that is divided into 9 evenly sized blocks or sub-grids.
- The grid is centered on the audio frequency output transducer of the WD (speaker or T-coil).
- The grid is located by reference to a reference plane. This reference plane is the planar area that contains the highest point in the area of the WD that normally rests against the user's ear
- •The measurement plane is located parallel to the reference plane and 15 mm from it, out from the phone. The grid is located in the measurement plane.

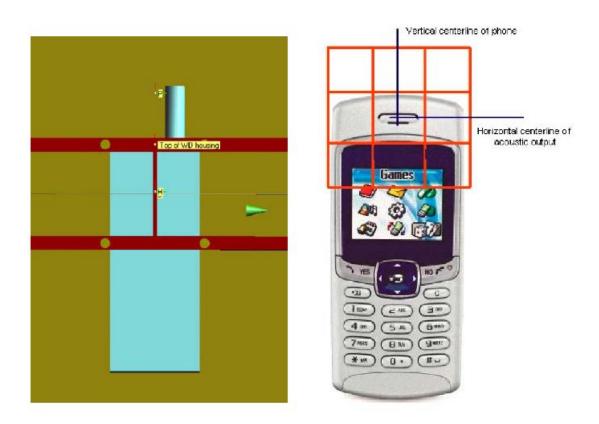


Fig. 3 WD reference and plane for RF emission measurements



8 SYSTEM VALIDATION

8.1 Validation Procedure

Place a dipole antenna meeting the requirements given in ANSI C63.19 in the position normally occupied by the WD. The dipole antenna serves as a known source for an electrical output. Position the E-field probes so that:

- •The probes and their cables are parallel to the coaxial feed of the dipole antenna
- •The probe cables and the coaxial feed of the dipole antenna approach the measurement area from opposite directions
- The center point of the probe element(s) are 15 mm from the closest surface of the dipole elements.

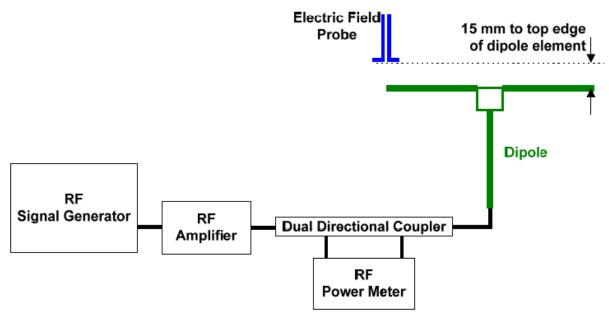


Fig. 4 Dipole Validation Setup

8.2 Validation Result

	E-Field Scan					
Mode	Frequency	Input Power	Measured ¹	Target ²	Deviation ³	Limit ⁴
	(MHz)	(mW)	Value(dBV/m)	Value(dBV/m)	(%)	(%)
CW	835	100	40.59	40.54	0.58	±25
CW	1880	100	39.58	39.35	2.68	±25

Notes:

- 1. Please refer to the attachment for detailed measurement data and plot.
- 2. Target value is provided by SPEAD in the calibration certificate of specific dipoles.
- 3. Deviation (%) = 100 * (Measured value minus Target value) divided by Target value.
- 4. ANSI C63.19 requires values within \pm 25% are acceptable, of which 12% is deviation and 13% is measurement uncertainty. Values independently validated for the dipole actually used in the measurements should be used, when available.



9 Evaluation of MIF

9.1 Introduction

The MIF (Modulation Interference Factor) is used to classify E-field emission to determine Hearing Aid Compatibility (HAC). It scales the power-averaged signal to the RF audio interference level and is characteristic to a modulation scheme. The HAC standard preferred "indirect" measurement method is based on average field measurement with separate scaling by the MIF. With an Audio Interference Analyzer (AIA) designed by SPEAG specifically for the MIF measurement, these values have been verified by practical measurements on an RF signal modulated with each of the waveforms. The resulting deviations from the simulated values are within the requirements of the HAC standard.

The AIA (Audio Interference Analyzer) is an USB powered electronic sensor to evaluate signals in the frequency range 698MHz - 6 GHz. It contains RMS detector and audio frequency circuits for sampling of the RF envelope.

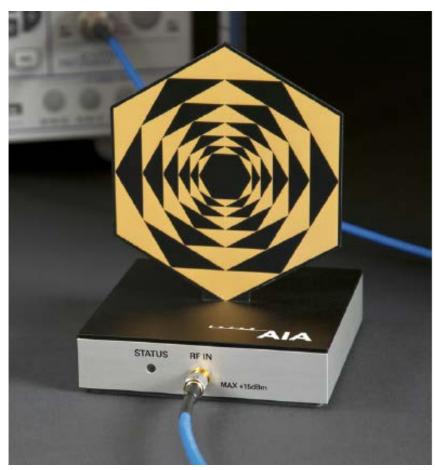


Fig. 5 AIA Front View



9.2 MIF measurement with the AIA

The MIF is measured with the AIA as follows:

- 1. Connect the AIA via USB to the DASY5 PC and verify the configuration settings.
- 2. Couple the RF signal to be evaluated to an AIA via cable or antenna.
- 3. Generate a MIF measurement job for the unknown signal and select the measurement port and timing settings.
- 4. Document the results via the post processor in a report.

9.3 Test equipment for the MIF measurement

No.	Name	Туре	Serial Number	Manufacturer
01	Signal Generator	E4438C	MY49071430	Agilent
02	AIA	SE UMS 170 CB	1029	SPEAG
03	BTS	E5515C	MY50263375	Agilent

9.4 Test signal validation

The signal generator (E4438C) is used to generate a 1GHz signal with different modulation in the below table based on the ANSI C63.19-2011. The measured MIF with AIA are compared with the target values given in ANSI C63.19-2011 table D.3, D.4 and D5.

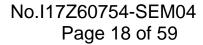
Pulse modulation	Target MIF	Measured MIF	Deviation
0.5ms pulse, 1000Hz repetition rate	-0.9 dB	-0.9 dB	0 dB
1ms pulse, 100Hz repetition rate	+3.9 dB	+3.7 dB	0.2 dB
0.1ms pulse, 100Hz repetition rate	+10.1 dB	+10.0 dB	0.1 dB
10ms pulse, 10Hz repetition rate	+1.6 dB	+1.7 dB	0.1 dB
Sine-wave modulation	Target MIF	Measured MIF	Deviation
1 kHz, 80% AM	-1.2 dB	-1.3 dB	0.1 dB
1 kHz, 10% AM	-9.1 dB	-9.0 dB	0.1 dB
1 kHz, 1% AM	-19.1 dB	-18.9 dB	0.2 dB
100 Hz, 10% AM	-16.1 dB	-16.0 dB	0.1 dB
10 kHz, 10% AM	-21.5 dB	-21.6 dB	0.1 dB
Transmission protocol	Target MIF	Measured MIF	Deviation
GSM; full-rate version 2; speech codec/handset low	+3.5 dB	+3.47 dB	0.03 dB
WCDMA; speech; speech codec low; AMR 12.2 kb/s	-20.0 dB	-19.8 dB	0.2 dB
CDMA; speech; SO3; RC3; full frame rate; 8kEVRC	-19.0 dB	-19.1 dB	0.1 dB
CDMA; speech; SO3; RC1; 1/8 th frame rate; 8kEVRC	+3.3 dB	+3.44 dB	0.14 dB



9.5 DUTMIF results

Typical MIF levels in ANSI C63.19-2011			
Transmission protocol	Modulation interference factor		
GSM; full-rate version 2; speech codec/handset low	+3.5 dB		
WCDMA; speech; speech codec low; AMR 12.2 kb/s	-20.0 dB		
LTE-FDD (SC-FDMA, 1RB, 20MHz, QPSK)	-15.63 dB		
LTE-FDD (SC-FDMA, 1RB, 20MHz, 16QAM)	-9.76 dB		
LTE-TDD (SC-FDMA, 1RB, 20MHz, QPSK)	-1.62 dB		
LTE-TDD (SC-FDMA, 1RB, 20MHz, 16QAM)	-1.44 dB		

	Measured MIF lev	els
Band	Channel	Modulation interference factor
	251	+3.21 dB
GSM 850	190	+3.44 dB
	128	+3.41 dB
	810	+3.44 dB
GSM 1900	661	+3.51 dB
	512	+3.51 dB
	4233	-14.92 dB
WCDMA 850	4182	-14.74 dB
	4132	-14.77 dB
	1513	-14.85 dB
WCDMA 1700	1412	-14.72 dB
	1312	-14.80 dB
	9538	-13.57 dB
WCDMA 1900	9400	-15.23 dB
	9262	-15.08 dB
LTE D IO	19100	-14.83 dB
LTE Band2	18900	-15.16 dB
QPSK	18700	-13.87 dB
1.75.5	20300	-14.86 dB
LTE Band4	20175	-15.64 dB
QPSK	20050	-15.05 dB
1.75.5	21350	-15.63 dB
LTE Band7	21100	-15.73 dB
QPSK	20850	-15.47 dB
LTE D. 140	23130	-15.25 dB
LTE Band12	23095	-15.03 dB
QPSK —	23060	-15.15 dB
LTE D	23800	-15.23 dB
LTE Band17	23790	-15.18 dB
QPSK	23780	-15.41 dB
LTE Day 100	38150	-15.18 dB
LTE Band38	38000	-15.07 dB
QPSK —	37850	-15.29 dB
LTE D !?	19100	-10.72 dB
LTE Band2	18900	-9.91 dB
16QAM	18700	-10.75 dB





LTE Band4	20300	-10.92 dB
16QAM	20175	-11.07 dB
TOQAW	20050	-10.46 dB
LTE Band7	21350	-10.99 dB
16QAM	21100	-10.28 dB
TOQAW	20850	-11.03 dB
LTE Band12	23130	-11.19 dB
16QAM	23095	-10.41 dB
TOQAIVI	23060	-9.80 dB
LTE Band17	23800	-11.20 dB
16QAM	23790	-10.20 dB
TOQAIVI	23780	-9.75 dB
LTE Band38	38150	-10.03 dB
16QAM	38000	-9.78 dB
TOQAW	37850	-10.27 dB



10 Evaluation for low-power exemption

10.1 Product testing threshold

There are two methods for exempting an RF air interface technology from testing. The first method requires evaluation of the MIF for the worst-case operating mode. An RF air interface technology of a device is exempt from testing when its average antenna input power plus its MIF is \leq 17 dBm for any of its operating modes. The second method does not require determination of the MIF. The RF emissions testing exemption shall be applied to an RF air interface technology in a device whose peak antenna input power, averaged over intervals \leq 50 μ s20, is \leq 23 dBm. An RF air interface technology that is exempted from testing by either method shall be rated as M4. The first method is used to be exempt from testing for the RF air interface technology in this report.

10.2 Conducted power

Band	Average power (dBm)	MIF (dB)	Sum (dBm)
GSM 850	33.39	+3.44	36.83
GSM 1900	30.48	+3.51	33.99
WCDMA 850	24.35	-14.74	9.61
WCDMA 1700	23.93	-14.72	9.21
WCDMA 1900	24.15	-13.57	10.58

10.3 Conclusion

According to the above table, the sums of average power and MIF for UMTS are less than 17dBm. So it is measured for GSM bands. The UMTS bands are exempt from testing and rated as M4.



11 RF TEST PROCEDUERES

The evaluation was performed with the following procedure:

- 1) Confirm proper operation of the field probe, probe measurement system and other instrumentation and the positioning system.
- 2) Position the WD in its intended test position. The gauge block can simplify this positioning.
- 3) Configure the WD normal operation for maximum rated RF output power, at the desired channel and other operating parameters (e.g., test mode), as intended for the test.
- 4) The center sub-grid shall centered on the center of the T-Coil mode axial measurement point or the acoustic output, as appropriate. Locate the field probe at the initial test position in the50 mm by 50 mm grid, which is contained in the measurement plane. If the field alignment method is used, align the probe for maximum field reception.
- 5) Record the reading.
- 6) Scan the entire 50 mm by 50 mm region in equally spaced increments and record the reading at each measurement point. The distance between measurement points shall be sufficient to assure the identification of the maximum reading.
- 7) Identify the five contiguous sub-grids around the center sub-grid whose maximum reading is the lowest of all available choices. This eliminates the three sub-grids with the maximum readings. Thus, the six areas to be used to determine the WD's highest emissions are identified.
- 8) Identify the maximum field reading within the non-excluded sub-grids identified in Step 7)
- 9) Evaluate the MIF and add to the maximum steady-state rms field-strength reading to obtain the RF audio interference level..
- 10) Compare this RF audio interference level with the categories and record the resulting WD category rating.



12 Measurement Results (E-Field)

Fred	quency	Measured	Measured Power Prift (dR)		
MHz	Channel	Value(dBV/m)	Power Drift (dB)	Category	
	GSM 850				
848.8	251	34.14	-0.01	M4 (see Fig B.1)	
836.6	190	34.41	0.00	M4 (see Fig B.2)	
824.2	128	34.50	0.03	M4 (see Fig B.3)	
		GSM 19	00		
1909.8	810	27.79	0.00	M4 (see Fig B.4)	
1880	661	28.44	0.14	M4 (see Fig B.5)	
1850.2	512	28.15	-0.07	M4 (see Fig B.6)	

13 ANSIC 63.19-2011 LIMITS

WD RF audio interference level categories in logarithmic units

Emission categories	< 960	< 960 MHz	
	E-field e	E-field emissions	
Category M1	50 to 55	dB (V/m)	
Category M2	45 to 50	dB (V/m)	
Category M3	40 to 45	dB (V/m)	
Category M4	< 40	dB (V/m)	
Emission categories	>960	MHz	
	E-field e	missions	
Category M1	40 to 45	dB (V/m)	
Category M2	35 to 40	dB (V/m)	
Category M3	30 to 35	dB (V/m)	
Category M4	< 30	dB (V/m)	



14 MEASUREMENT UNCERTAINTY

No.	Error source	Туре	Uncertainty Value(%)	Prob. Dist.	k	c _i E	Standard Uncertainty (%) $u_i^{'}$ (%)E	Degree of freedom V _{eff} or <i>v</i> _i
	urement System	В		NI.	4		F.4	∞
1	Probe Calibration	В	5.	N	1	1	5.1	- ω
2	Axial Isotropy	В	4.7	R	$\sqrt{3}$	1	2.7	∞
3	Sensor Displacement	В	16.5	R	$\sqrt{3}$	1	9.5	∞
4	Boundary Effects	В	2.4	R	$\sqrt{3}$	1	1.4	∞
5	Linearity	В	4.7	R	$\sqrt{3}$	1	2.7	∞
6	Scaling to Peak Envelope Power	В	2.0	R	$\sqrt{3}$	1	1.2	∞
7	System Detection Limit	В	1.0	R	$\sqrt{3}$	1	0.6	∞
8	Readout Electronics	В	0.3	N	1	1	0.3	∞
9	Response Time	В	0.8	R	$\sqrt{3}$	1	0.5	∞
10	Integration Time	В	2.6	R	$\sqrt{3}$	1	1.5	8
11	RF Ambient Conditions	В	3.0	R	$\sqrt{3}$	1	1.7	∞
12	RF Reflections	В	12.0	R	$\sqrt{3}$	1	6.9	∞
13	Probe Positioner	В	1.2	R	$\sqrt{3}$	1	0.7	∞
14	Probe Positioning	Α	4.7	R	$\sqrt{3}$	1	2.7	∞
15	Extra. And Interpolation	В	1.0	R	$\sqrt{3}$	1	0.6	∞
Test	Sample Related					•		
16	Device Positioning Vertical	В	4.7	R	$\sqrt{3}$	1	2.7	8
17	Device Positioning Lateral	В	1.0	R	$\sqrt{3}$	1	0.6	∞
18	Device Holder and Phantom	В	2.4	R	$\sqrt{3}$	1	1.4	∞
19	Power Drift	В	5.0	R	$\sqrt{3}$	1	2.9	∞



20	AIA measurement	В	12	R	$\sqrt{3}$	1	6.9	∞
Pha	ntom and Setup related							
21	Phantom Thickness	В	2.4	R	$\sqrt{3}$	1	1.4	∞
Coml	Combined standard uncertainty(%) 16.2							
1	nded uncertainty idence interval of 95 %)	ι	$u_e = 2u_c$	Z	k=	2	32.4	

15 MAIN TEST INSTRUMENTS

Table 1: List of Main Instruments

No.	Name	Туре	Serial Number	Calibration Date	Valid Period	
01	Signal Generator	E4438C	MY49071430	January 13,2017	One Year	
02	Power meter	NRVD	102083	Contombor 22 2016	One year	
03	Power sensor	NRV-Z5	100595	September 22,2016	One year	
04	Amplifier	60S1G4	0331848	No Calibration Requested		
05	E-Field Probe	ER3DV6	2428	January 19, 2017	One year	
06	HAC Dipole	CD835V3	1023	August 31, 2016	One year	
07	HAC Dipole	CD1880V3	1018	August 31, 2016	One year	
08	BTS	E5515C	MY50263375	January 16, 2017	One year	
09	DAE	SPEAG DAE4	777	August 22, 2016	One year	
10	AIA	SE UMS 170 CB	1029	No Calibration Requested		

16 CONCLUSION

The HAC measurement indicates that the EUT complies with the HAC limits of the ANSIC63.19-2011. The total M-rating is **M4.**

END OF REPORT BODY



ANNEX A TEST LAYOUT



Picture A1:HAC RF System Layout



ANNEX BTEST PLOTS

HAC RF E-Field GSM 850 High

Date: 2017-5-22

Electronics: DAE4 Sn777

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature: 22.0°C

Communication System: GSM 850; Frequency: 848.8 MHz; Duty Cycle: 1:8.3

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

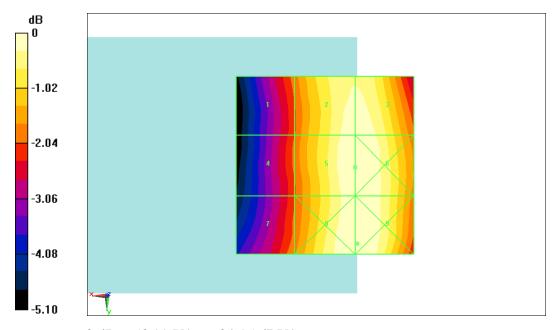
Reference Value = 39.78 V/m; Power Drift = -0.01 dB

Applied MIF = 3.21 dB

RF audio interference level = 34.14 dBV/m

Emission category: M4

Grid 1 M4	Grid 2 M4	Grid 3 M4
32.32 dBV/m	34.01 dBV/m	34.01 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
32.23 dBV/m	34.14 dBV/m	34.14 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
32.45 dBV/m	34.15 dBV/m	34.15 dBV/m



0 dB = 50.99 V/m = 34.15 dBV/m

Fig B.1 HAC RF E-Field GSM 850 High



HAC RF E-Field GSM 850 Middle

Date: 2017-5-22

Electronics: DAE4 Sn777

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature: 22.0°C

Communication System: GSM 850; Frequency: 836.6 MHz; Duty Cycle: 1:8.3

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device 2/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

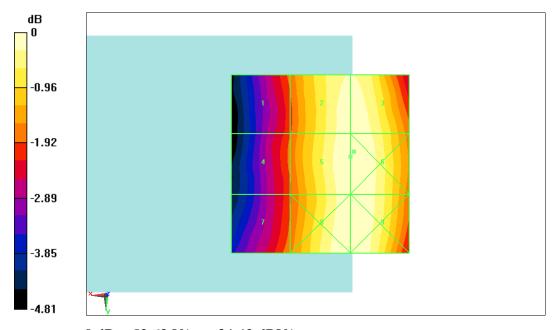
Reference Value = 39.86 V/m; Power Drift = 0.00 dB

Applied MIF = 3.44 dB

RF audio interference level = 34.41 dBV/m

Emission category: M4

Grid 1 M4	Grid 2 M4	Grid 3 M4
32.63 dBV/m	34.32 dBV/m	34.33 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
32.61 dBV/m	34.41 dBV/m	34.42 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
32.76 dBV/m	34.4 dBV/m	34.41 dBV/m



0 dB = 52.62 V/m = 34.42 dBV/m

Fig B.2 HAC RF E-Field GSM 850 Middle



HAC RF E-Field GSM 850 Low

Date: 2017-5-22

Electronics: DAE4 Sn777

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature: 22.0°C

Communication System: GSM 850; Frequency: 824.2 MHz; Duty Cycle: 1:8.3

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device 3/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

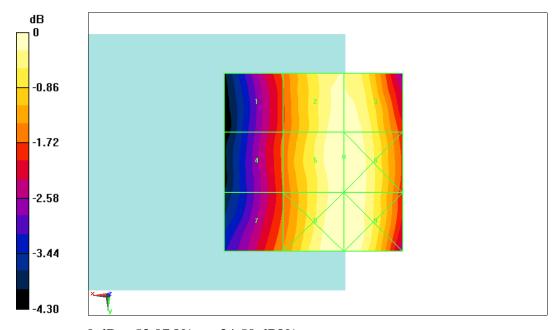
Reference Value = 40.51 V/m; Power Drift = 0.03 dB

Applied MIF = 3.41 dB

RF audio interference level = 34.50 dBV/m

Emission category: M4

Grid 1 M4	Grid 2 M4	Grid 3 M4
32.88 dBV/m	34.38 dBV/m	34.37 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
32.89 dBV/m	34.5 dBV/m	34.5 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
33.11 dBV/m	34.5 dBV/m	34.5 dBV/m



0 dB = 53.07 V/m = 34.50 dBV/m

Fig B.3 HAC RF E-Field GSM 850 Low



HAC RF E-Field GSM 1900 High

Date: 2017-5-22

Electronics: DAE4 Sn777

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature: 22.0°C

Communication System: DCS 1900; Frequency: 1909.8 MHz; Duty Cycle: 1:8.3

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

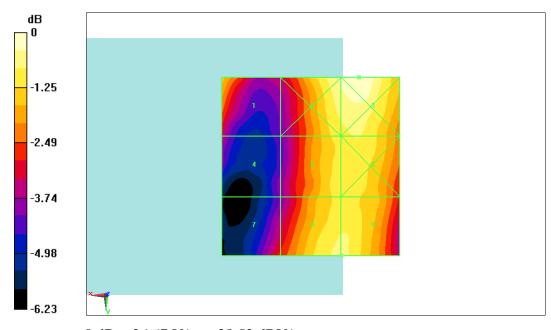
Reference Value = 15.31 V/m; Power Drift = 0.00 dB

Applied MIF = 3.44 dB

RF audio interference level = 27.79 dBV/m

Emission category: M4

Grid 1 M4	Grid 2 M4	Grid 3 M4
27.14 dBV/m	28.24 dBV/m	28.52 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
25.21 dBV/m	27.53 dBV/m	27.7 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
25.81 dBV/m	27.79 dBV/m	27.79 dBV/m



0 dB = 26.67 V/m = 28.52 dBV/m

Fig B.4 HAC RF E-Field GSM 1900 High



HAC RF E-Field GSM 1900 Middle

Date: 2017-5-22

Electronics: DAE4 Sn777

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature: 22.0°C

Communication System: DCS 1900; Frequency: 1880 MHz; Duty Cycle: 1:8.3

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device 2/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

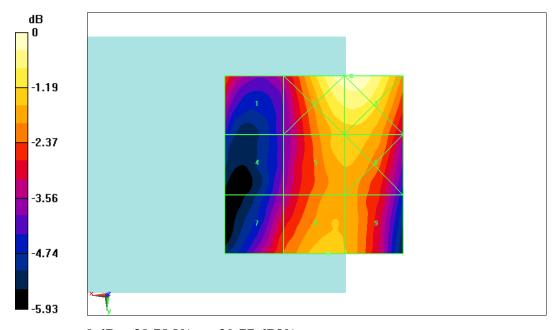
Reference Value = 17.43 V/m; Power Drift = 0.14 dB

Applied MIF = 3.51 dB

RF audio interference level = 28.44 dBV/m

Emission category: M4

Grid 1 M4	Grid 2 M4	Grid 3 M4
27.52 dBV/m	29.69 dBV/m	29.76 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
26.22 dBV/m	28.42 dBV/m	28.44 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
27.44 dBV/m	28.44 dBV/m	28.26 dBV/m



0 dB = 30.78 V/m = 29.77 dBV/m

Fig B.5 HAC RF E-Field GSM 1900 Middle



HAC RF E-Field GSM 1900 Low

Date: 2017-5-22

Electronics: DAE4 Sn777

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature: 22.0°C

Communication System: DCS 1900; Frequency: 1850.2 MHz; Duty Cycle: 1:8.3

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device 3/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

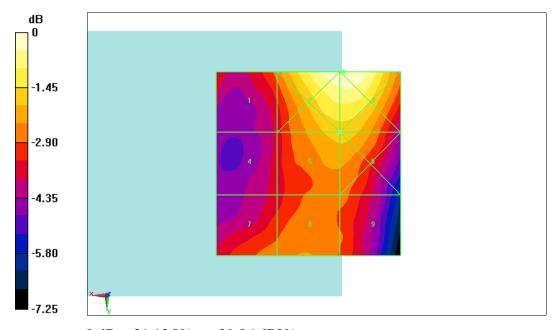
Reference Value = 16.81 V/m; Power Drift = -0.07 dB

Applied MIF = 3.51 dB

RF audio interference level = 28.15 dBV/m

Emission category: M4

Grid 1 M4	Grid 2 M4	Grid 3 M4
27.22 dBV/m	29.86 dBV/m	29.86 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
26.28 dBV/m	28.15 dBV/m	28.16 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
27.35 dBV/m	27.53 dBV/m	27.14 dBV/m



0 dB = 31.13 V/m = 29.86 dBV/m

Fig B.6 HAC RF E-Field GSM 1900 Low



ANNEX C SYSTEM VALIDATION RESULT

E SCAN of Dipole 835 MHz

Date: 2017-5-22

Electronics: DAE4 Sn777

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon r = 1$; $\rho = 1000$ kg/m3 Communication System: CW; Frequency: 835 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - measurement distance from the probe sensor center to CD835 Dipole = 15mm/Hearing Aid Compatibility Test (41x361x1): Interpolated grid: dx=0.5000 mm,

dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 107.1 V/m; Power Drift = -0.04 dB

Applied MIF = 0.00 dB

RF audio interference level = 40.59 dBV/m

Emission category: M3

Grid 1M3	Grid 2M3	Grid 3 M3
40.39 dBV/m	40.59 dBV/m	40.47 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
35.58 dBV/m	35.89 dBV/m	35.88 dBV/m
Grid 7 M3	Grid 8 M3	Grid 9 M3
39.99 dBV/m	40.29 dBV/m	40.23 dBV/m



0 dB = 40.59 dBV/m



E SCAN of Dipole 1880 MHz

Date: 2017-5-22

Electronics: DAE4 Sn777

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Communication System: CW; Frequency: 1880 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - measurement distance from the probe sensor center to CD1880 Dipole = 15mm/Hearing Aid Compatibility Test (41x181x1): Interpolated grid: dx=0.5000 mm,

dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

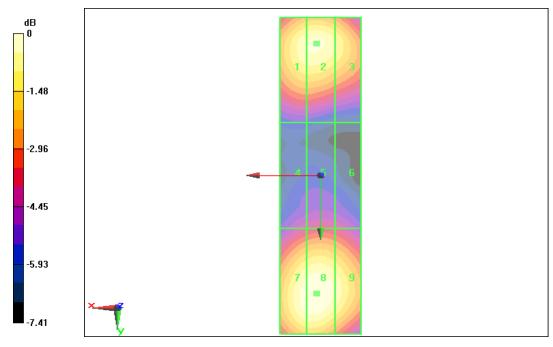
Reference Value = 95.7 V/m; Power Drift = 0.03 dB

Applied MIF = 0.00 dB

RF audio interference level = 39.58 dBV/m

Emission category: M2

Grid 1M2	Grid 2 M2	Grid 3 M2
39.35dBV/m	39.58dBV/m	39.45dBV/m
Grid 4M2	Grid 5M2	Grid 6 M2
37.02dBV/m	37.20dBV/m	37.13dBV/m
Grid 7M2	Grid 8 M2	Grid 9 M2
39.38dBV/m	39.52dBV/m	39.42dBV/m



0 dB = 39.58 dBV/m



ANNEX D PROBE CALIBRATION CERTIFICATE

E_Probe ER3DV6

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Client

CTTL (Auden)

Certificate No: ER3-2428_Jan17

CALIBRATION CERTIFICATE

ER3DV6 - SN:2428 Object

QA CAL-02.v8, QA CAL-25.v6 Calibration procedure(s)

Calibration procedure for E-field probes optimized for close near field

evaluations in air

January 19, 2017 Calibration date:

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID	Cal Date (Certificate No.)	Scheduled Calibration
Power meter NRP	SN: 104778	06-Apr-16 (No. 217-02288/02289)	Apr-17
Power sensor NRP-Z91	SN: 103244	06-Apr-16 (No. 217-02288)	Apr-17
Power sensor NRP-Z91	SN: 103245	06-Apr-16 (No. 217-02289)	Apr-17
Reference 20 dB Attenuator	SN: S5277 (20x)	05-Apr-16 (No. 217-02293)	Apr-17
Reference Probe ER3DV6	SN: 2328	14-Oct-16 (No. ER3-2328_Oct16)	Oct-17
DAE4	SN: 789	11-Nov-16 (No. DAE4-789_Nov16)	Nov-17
Secondary Standards	ID	Check Date (in house)	Scheduled Check
Power meter E4419B	SN: GB41293874	06-Apr-16 (in house check Jun-16)	In house check: Jun-18
Power sensor E4412A	SN: MY41498087	06-Apr-16 (in house check Jun-16)	In house check: Jun-18
Power sensor E4412A	SN: 000110210	06-Apr-16 (in house check Jun-16)	In house check: Jun-18
RF generator HP 8648C	SN: US3642U01700	04-Aug-99 (in house check Jun-16)	In house check: Jun-18
Network Analyzer HP 8753E	SN: US37390585	18-Oct-01 (in house check Oct-16)	In house check: Oct-17

	Name	Function	Signature
Calibrated by:	Jeton Kastrati	Laboratory Technician	7-102
Approved by:	Katja Pokovic	Technical Manager	DE RY
			Issued: January 21, 2017

Certificate No: ER3-2428_Jan17 Page 1 of 10





Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland







Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Glossary:

NORMx,y,z sensitivity in free space diode compression point

CF crest factor (1/duty_cycle) of the RF signal A, B, C, D modulation dependent linearization parameters

Polarization ϕ ϕ rotation around probe axis

Polarization 9 9 rotation around an axis that is in the plane normal to probe axis (at measurement center),

i.e., $\theta = 0$ is normal to probe axis

Connector Angle information used in DASY system to align probe sensor X to the robot coordinate system

Calibration is Performed According to the Following Standards:

- IEEE Std 1309-2005, "IEEE Standard for calibration of electromagnetic field sensors and probes, excluding antennas, from 9 kHz to 40 GHz", December 2005
- b) CTIA Test Plan for Hearing Aid Compatibility, Rev 3.0, November 2013

Methods Applied and Interpretation of Parameters:

- NORMx,y,z: Assessed for E-field polarization 9 = 0 for XY sensors and 9 = 90 for Z sensor (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide).
- NORM(f)x,y,z = NORMx,y,z * frequency_response (see Frequency Response Chart).
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics
- Ax,y,z; Bx,y,z; Cx,y,z; Dx,y,z; VRx,y,z: A, B, C, D are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- Spherical isotropy (3D deviation from isotropy): in a locally homogeneous field realized using an open waveguide setup.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).

Certificate No: ER3-2428_Jan17 Page 2 of 10



ER3DV6 - SN:2428

January 19, 2017

Probe ER3DV6

SN:2428

Manufactured: Calibrated:

September 11, 2007 January 19, 2017

Calibrated for DASY/EASY Systems (Note: non-compatible with DASY2 system!)

Certificate No: ER3-2428_Jan17

Page 3 of 10